

Fig. 1a

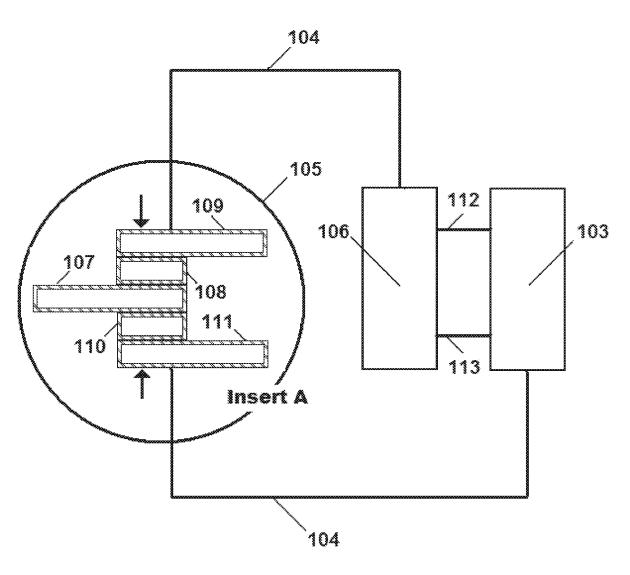


Fig. 1b

Fig. 3 Fig. 2 HOT AND COLD LAYERS **HOT AND COLD LAYERS METAL BAR STOCK PROCCESS POWDER METAL PROCCESS** Cut hot and cold layers to Form hot and cold layers under appropriate size. [201] pressure into appropriate size and density of 88-98% using copper powder material in the micro to nanometer size range. [301] Coat layers using atactic Sinter and anneal hot and cold layers in reducing atmosphere polypropylene or propylene glycol coating processes. [202] near the melting temperature of copper. [302] Cure coating using superconducting Coat hot and cold layer using polymer curing process [203] atactic polypropylene or propylene glycol - coating processes [303] Cure coating using superconducting polymer curing process [304]

Fig. 4

HOT AND COLD LAYERS PROCESS WITH INTEGRAL SEMICONDUCTOR LAYER

Supply formed layers. [401]

| Deposit a layer of N-Type or P-Type semiconductor material using but not limited to electro plating, vapor deposition, vacuum deposition or plasma sputtering processes. [402a]

| Alternative to [402a] deposit a composite layer of N-Type or P-Type semiconductor material particles suspended in a polymer using any appropriate process. [402b]

| Coat semiconductor layer using atactic polypropylene or propylene glycol - coating processes [403]

| Cure coating using the superconducting polymer curing process [404]

Fig. 5

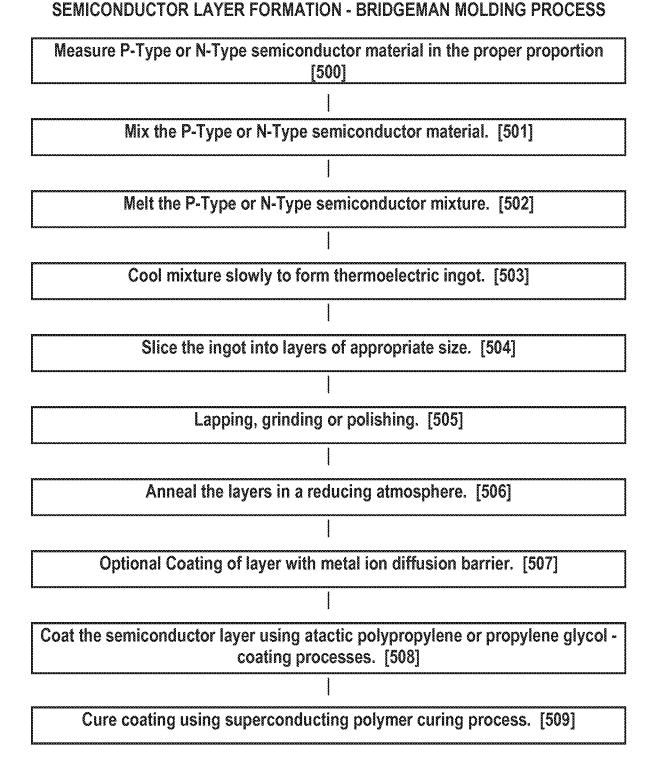


Fig. 6

SEMICONDUCTOR LAYER FORMATION and CONCURRENT SUPERCONDUCTING POLYMER COATING

DIRECT MELTING PROCESS

Measure P-Type or N-Type semiconductor material in the proper proportion. [601]
Melt measured semiconductor material in carbon crucible. [602]
Form mold cavity the thickness of finished layers from fly ash, sand or other mold material with propylene glycol or Atactic Polypropylene solution. [603]
Pour molten measured semiconductor material into mold. [604]
Heated solution produces thick white fumes as semiconductor material cools. [605]
Remove coated semiconductor material from mold. [606]
Cut material into appropriate layer sizes. [607]

Fig. 7 SEMICONDUCTOR LAYER FORMATION

POWDERED METAL PROCESS

Measure P-Type or N-Type semiconductor material in the proper proportion. [701]
Form measured semiconductor layers under pressure into appropriate size and density of 90-98% using powder semiconductor material in the micrometer to nanometer size range. [702]
Sinter and Anneal layer in reducing atmosphere at a temperature of near melting temperature. [703]
Perform Lapping, grinding or polishing of layer surfaces. [704]
Anneal layer in reducing atmosphere. [705]
Optional coating of layer with metal ion diffusion barrier. [706]
Coat layer using atactic polypropylene or propylene glycol - coating processes. [707]
Cure coating using superconducting polymer curing process. [708]

Fig. 8

PROPYLENE GLYCOL COATING PROCESS

Pour propylene glycol into container approximately 1/8 to 1/4" deep. [801]
Set screen into container suspended above the propylene glycol. [802]
Suspend recipient substrate on a screen that placed above the level of the propylene glycol. [803]
Cover the container partially. [804]
Apply heat until white fumes/mist fills the container. [805]
Fume/mist substrate for 20 minutes allowing propylene gerivative to form and coat the substrate. [806]
Cure coating using superconducting polymer curing process [807]

Fig. 9

ATACTIC POLYPROPYLENE COATING PROCESS

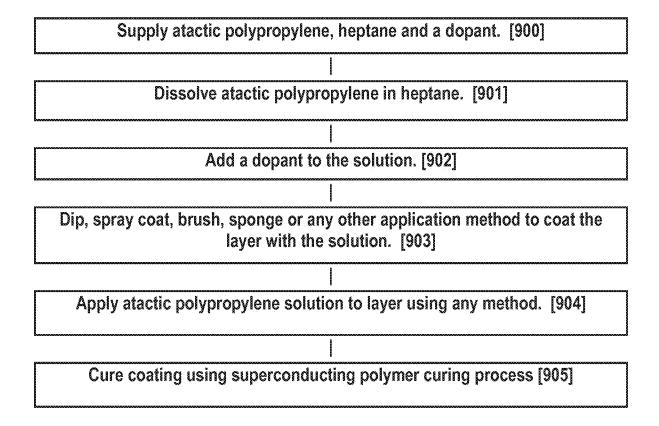


Fig. 10

SUPERCONDUCTING POLYMER CURING PROCESS

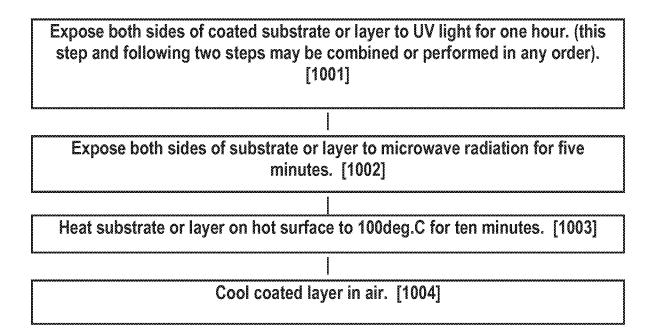


Fig. 11

ELECTRIC FIELD CONDITIONING ENERGY CONVERTER ASSEMBLLY

(to insure superconductivity and electrical contact between layers and coatings)

Connect the negative terminal of a power source (DC power supply or pulse width modulator) to all of the hot layers and the positive terminal to all of the cold layers, placing the P-Type and N-Type semiconductors in a parallel electrical circuit. [1101]

Energize the power source for a time that is a function of the paramaters of the apparatus to condition the conductive paths. [1102]

Energize the power source with the terminals reversed for a time that is a function of the paramaters of the apparatus to condition the semiconductor paths. [1103]

Confirm conditioning of entire apparatus by measuring its conductivity with the parallel circuit removed. [1104]

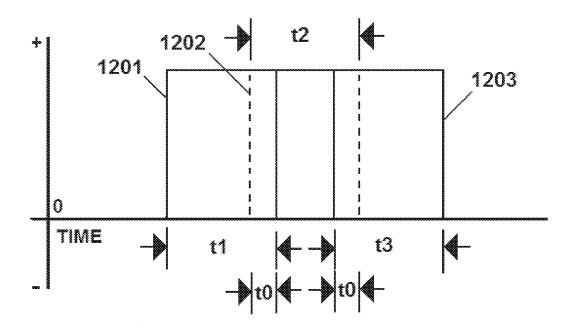
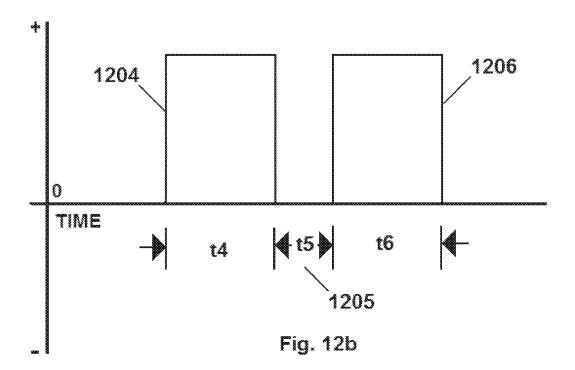


Fig. 12a



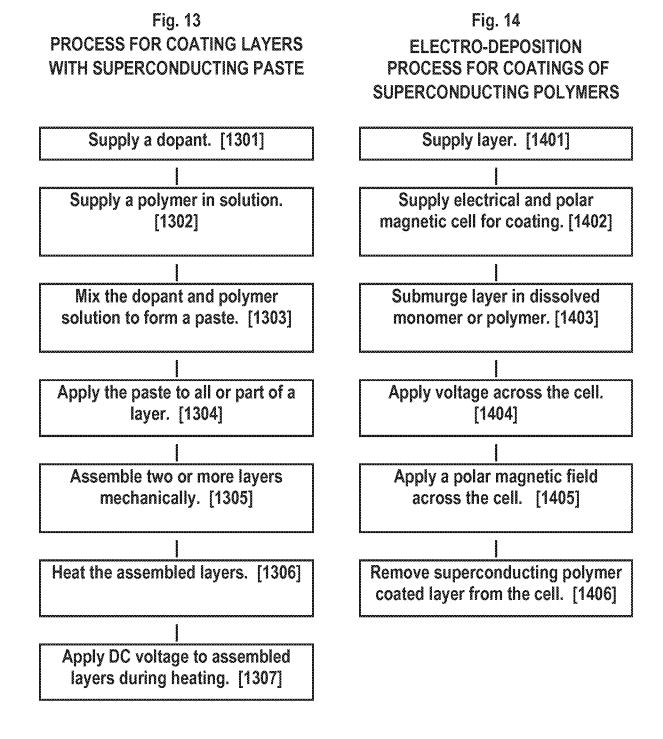


Fig. 15
SUPERCONDUCTING POLYMER COATING OF ASSEMBLED DEVICE USING ELECTRO-DEPOSITION PROCESS

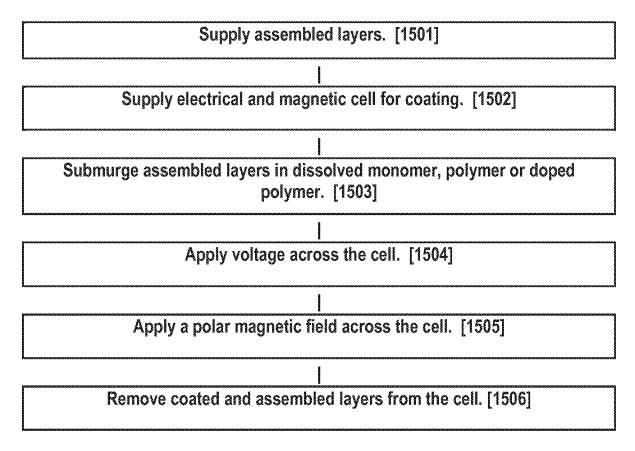


Fig. 16 SUPERCONDUCTING POLYMER COATING OF SEMICONDUCTOR LAYER

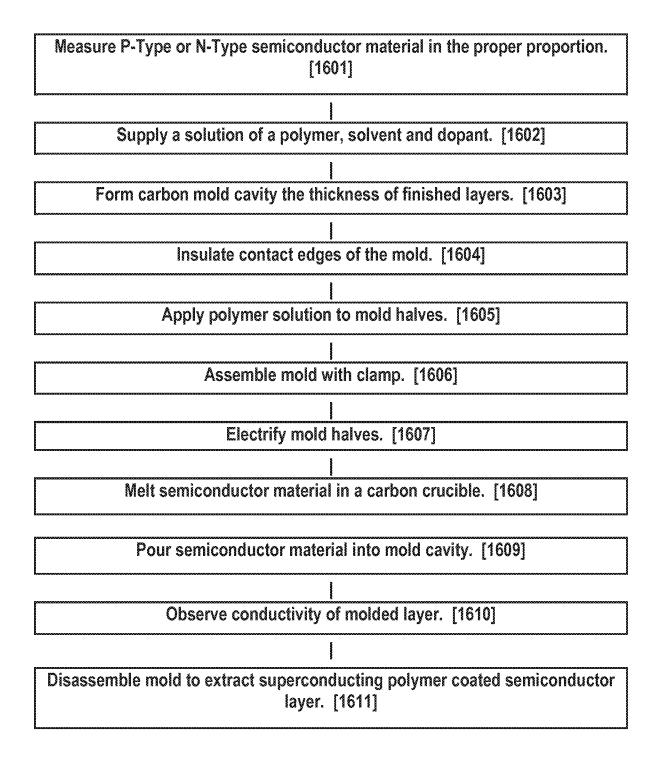


Fig. 17 ACTIVATING SUPERCONDUCTIVITY of DOPED POLYMER COATED LAYERS

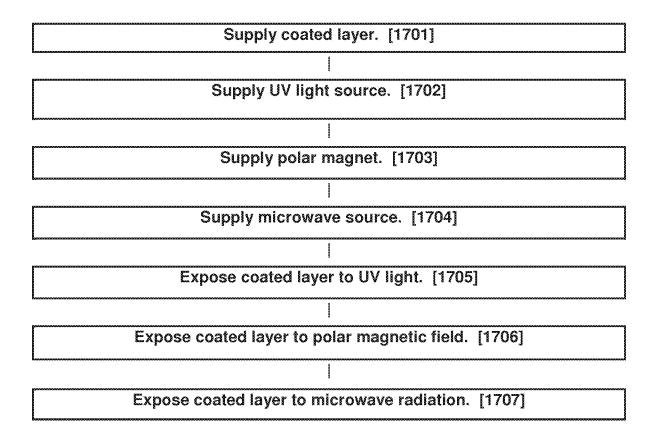
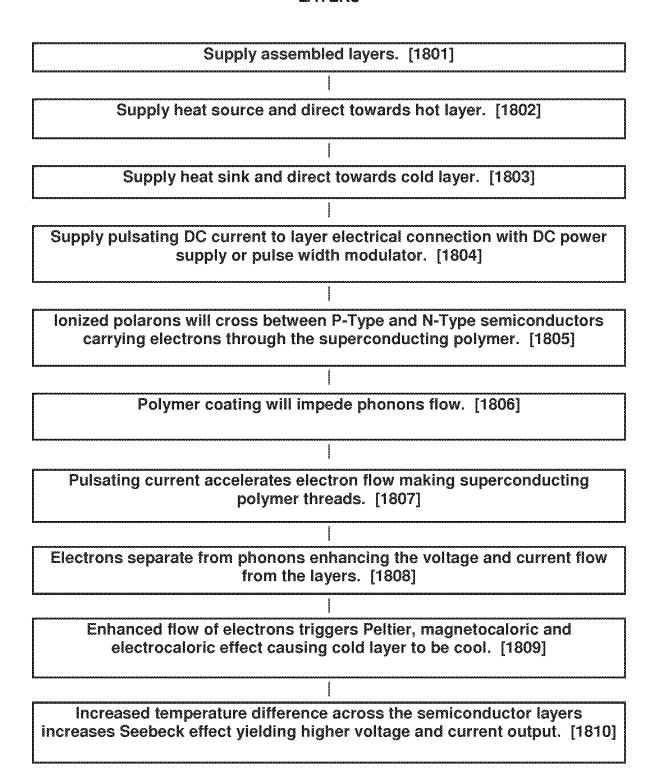


Fig. 18 FURTHER ACTIVATING SUPERCONDUCTIVITY of DOPED POLYMER COATED LAYERS



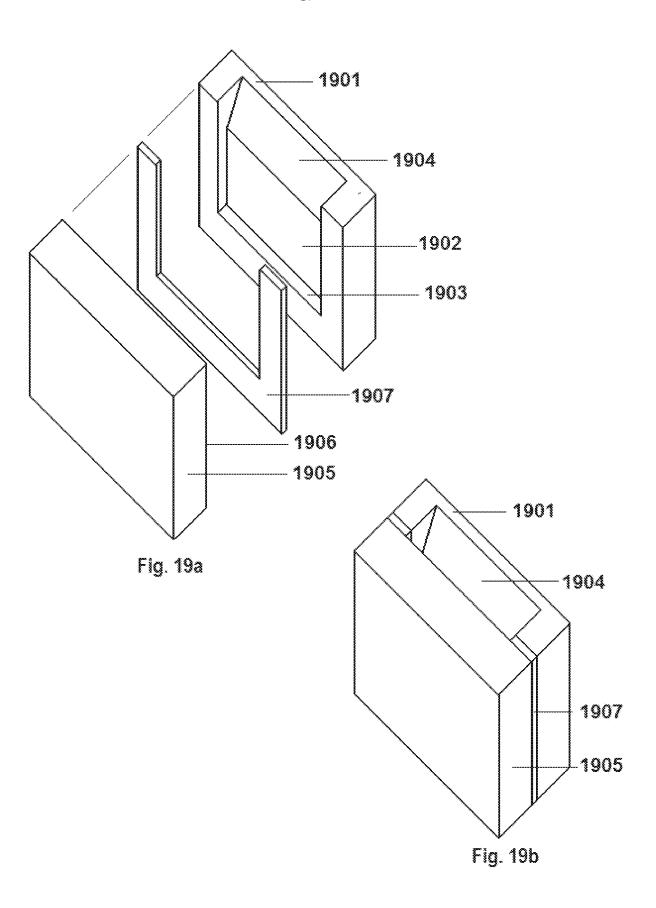


Fig. 20 CRYOGENIC MEMBER INSTALLATION PROCESS

Supply cryogenic cooling source operating at cryogenic temperature. [2001]
Supply thermoelectric stack requiring application of pressure to improve contact between layers. [2002]
Supply cryogenic treatable member having a smaller inner dimension than the outer dimension of the thermoelectric stack. [2003]
Cool cryogenic treatable member to cryogenic temperature in the cryogenic cooling source. [2004]
Supply a mechanical device for stretching cryogenic treatable members. [2005]
Stretch cryogenic treatable member to a larger inner dimension than the outer dimension of the thermoelectric stack. [2006]
Assemble cryogenic treatable member around thermoelectric stack before appreciable member temperature rise. [2007]
Allow cryogenically treatable member to warm to room temperature causing shrinkage of the member thereby applying pressure to the thermoelectric stack. [2008]

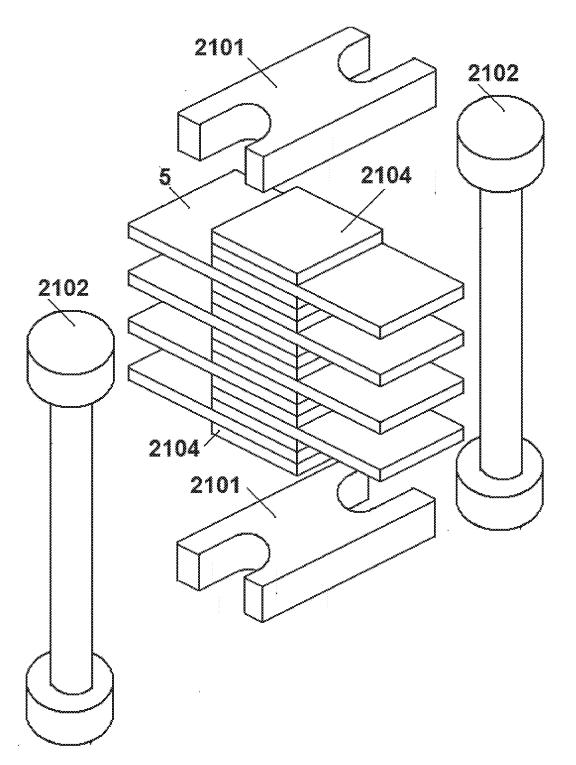


Fig. 21a

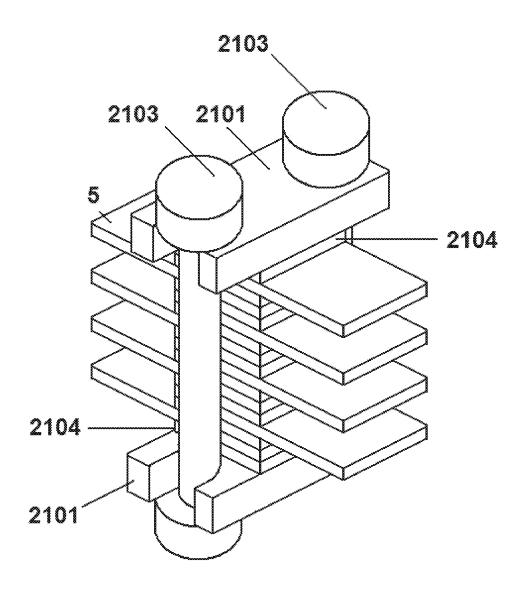


Fig. 21b